

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/591,206	IKEDA, MASAYUKI	
Examiner		Hai V. Nguyen	Art Unit 2618	Page 1 of 3	

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-5,844,525 A	12-1998	Hayes et al.	343/702
*	B US-6,075,500 A	06-2000	Kurz et al.	343/895
*	C US-6,218,991 B1	04-2001	Sanad, Mohamed	343/700MS
*	D US-6,239,749 B1	05-2001	Tzuang et al.	343/700MS
*	E US-6,259,407 B1	07-2001	Tran, Allen	343/700MS
*	F US-6,271,796 B1	08-2001	Itoh et al.	343/702
*	G US-6,424,820 B1	07-2002	Burdick et al.	455/41.1
*	H US-6,466,176 B1	10-2002	Maoz et al.	343/767
*	I US-2002/0175872 A1	11-2002	Apostolos, John T.	343/749
*	J US-2002/0183013 A1	12-2002	Auckland et al.	455/73
*	K US-2002/0180648 A1	12-2002	Boyle et al.	343/702
*	L US-6,535,170 B2	03-2003	Sawamura et al.	343/702
*	M US-2003/0142019 A1	07-2003	Hilgers, Achim	343/700.0MS

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/591,206

Applicant(s)/Patent Under

Reexamination

IKEDA, MASAYUKI

Examiner

Hai V. Nguyen

Art Unit

2618

Page 2 of 3

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,683,575 B2	01-2004	Sekine et al.	343/702
*	B US-6,765,536 B2	07-2004	Phillips et al.	343/702
*	C US-2004/0145529 A1	07-2004	Iguchi et al.	343/702
*	D US-6,822,611 B1	11-2004	Kontogeorgakis et al.	343/702
*	E US-6,845,253 B1	01-2005	Schantz, Hans Gregory	455/575.7
*	F US-6,895,255 B1	05-2005	Bridgelall, Raj	455/552.1
*	G US-6,911,944 B2	06-2005	Sekine et al.	343/702
*	H US-6,963,310 B2	11-2005	Horita et al.	343/702
*	I US-7,009,567 B2	03-2006	Iwai et al.	343/702
*	J US-7,034,750 B2	04-2006	Asakura et al.	343/700MS
*	K US-7,023,389 B2	04-2006	Demicco et al.	343/702
*	L US-2006/0097927 A1	05-2006	Satoh et al.	343/702
*	M US-7,102,578 B2	09-2006	Minemura, Takashi	343/702

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/591,206

Applicant(s)/Patent Under

Reexamination

IKEDA, MASAYUKI

Examiner

Hai V. Nguyen

Art Unit

2618

Page 3 of 3

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2006/0232492 A1	10-2006	Sawatani, Takuma	343/893
*	B US-7,164,386 B2	01-2007	Baliarda et al.	343/700MS
*	C US-7,245,950 B2	07-2007	Iwai et al.	455/575.7
*	D US-2007/0225053 A1	09-2007	Iwai et al.	455/575.7
*	E US-7,283,853 B2	10-2007	Kanazawa et al.	455/575.1
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.